
**Microbeam analysis — Selected
instrumental performance parameters
for the specification and checking of
energy-dispersive X-ray spectrometers
(EDS) for use with a scanning electron
microscope (SEM) or an electron
probe microanalyser (EPMA)**

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Foreword

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This document was prepared by Technical Committee ISO/TC 202, *Microbeam analysis*.

This third edition cancels and replaces the second edition (ISO 15632:2012), which has been technically revised. The main changes compared to the previous edition are as follows:

- The title has been detailed;
- The definition of *dead time* (3.4) is more detailed;
- A Note (including a new Reference [5]) has been added to General description (4.1) related to the net active sensor area;

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